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## The Magneto-Optical Voigt Parameter from Magneto-Optical Ellipsometry Data for Multilayer Samples with Single Ferromagnetic Layer

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Calculations of the magneto-optical Voigt parameter  $Q$  were carried out using various models of reflecting media for thin films Fe|SiO<sub>2</sub>|Si(100) samples using the data of the *in situ* magneto-ellipsometry. The obtained spectral dependences of  $Q$  make it possible to choose the algorithm for the analysis of experimental magneto-ellipsometry data and demonstrate that magneto-optical parameter  $Q$  of iron is thickness-dependent.

**Keywords:** magneto-optical Voigt parameter, magneto-optical ellipsometry, data processing, ferromagnetic layers, optical models, refractive index, extinction coefficient.

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